

Application/Control No.	Applicant(s)/Patent under Reexamination
09/703,181	MOORE ET AL.
Examiner	Art Unit
Phallaka Kik	2825

	SEARCHED				
Class	Subclass	Date	Examiner		
716	16,18,17	11/1/2004	PK		
326	41,47,101	11/1/2004	PK		
710	10	11/1/2004	PK		
713	1,100	11/1/2004	PK		
Above	updated	4/11/2005	PK		
Above	updated	8/23/2005	PK		
Above	search	8/23/2005	PK		
370	366	8/23/2005	PK		
709	221	8/23/2005	PK		
			·		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
716	16,17,18	8/23/2005	PK		
710	10	8/23/2005	PK		
713	1,100	8/23/2005	PK		
USP	370/366; 709/221 USPGPUB (see attached)		PK		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
BRS (EAST) USPAT, USPGPUB Cls/Sub searched: 716/1-18;326/38-45,47,63-81,101-103; 71-/10;713/1-100 (see attached)	11/1/2004	PK		
EPO, JPO, IBM TDB, Derwent (see attached)	11/1/2004	PK		
IEE/IEEE XPlore (see attached)	11/1/2004	PK		
USPAT, USPGPUB Updated searched: Class/Sub Searched: 716/1-18; 326/38-45,47,63-81,101-103; 71-/10; 713/1-100 (see attached)	4/11/2005	PK		
USPAT, USPGPUB Updated searched: Class/Sub Searched: 716/1-18; 326/38-45,47,63-81,101-103; 71-/10; 713/1-100 (see attached)	8/23/2005	. РК		
USPAT, USPGPUB New search: 716/1-18; 326/38-45,47,63-81,101- 103; 71-/10; 713/1-100; 370/all; 709/all (see attached)	8/23/2005	PK		
EPO, JPO, IBM TDB, Derwent New search (see attached)	8/23/2005	PK		
IEE/IEEE Xplore new search (see attached)	8/23/2005	PK		